

<b>Form 1449 (Modified)</b>		Atty Docket No.	BRIDP004
<b>Information Disclosure Statement By Applicant</b>		Application No.:	09/724,585
		Applicant	Beardslee et al.
		Filing Date	November 28, 2000
		Group	Unknown
(Use Several Sheets if Necessary)		Page 1 of 2	

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Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
OPE	A.	4,306,286	12/1981	Cocke et al.	703	15	
KWR	B.	4,590,581	05/1986	Widdoes, Jr.	703	2	
MAR 9 1 2001	C.	4,635,218	01/1987	Widdoes, Jr.	703	14	
KWR	D.	4,675,646	06/1987	Lauer	340	146.2	
KWR	E.	4,845,712	07/1989	Sanner et al.	714	736	
KWR	F.	4,901,259	02/1990	Watkins	703	2	
KWR	G.	4,937,770	06/1990	Samuels et al.	703	16	
KWR	H.	4,937,827	06/1990	Beck et al.	714	33	
KWR	I.	5,036,473	07/1991	Butts et al.	703	23	
KWR	J.	5,146,460	09/1992	Ackerman et al.	714	33	
KWR	K.	5,281,864	01/1994	Hahn et al.	—	—	
KWR	L.	5,321,828	06/1994	Phillips et al.	—	—	
KWR	M.	5,329,470	07/1994	Sample et al.	—	—	
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KWR	S.	5,560,009	09/1996	Lenkov et al.	—	—	
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KWR	V.	5,596,587	01/1997	Douglas et al.	—	—	
KWR	W.	5,640,542	06/1997	Whitsel et al.	—	—	
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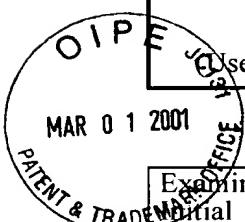
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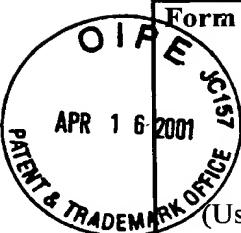
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KMN	JJ.	5,870,410	02/1999	Norman et al.	—	—	
KMN	KK.	5,907,697	05/1999	Barbier et al.	—	—	
KMN	LL.	5,937,190	08/1999	Gregory et al.	—	—	
KMN	MM.	5,943,490	08/1999	Sample	—	—	
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KJM	E.	6,182,247	01/2001	Herrmann et al.	714	39	

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—	F.	DE 4 042 262	07/1992	Germany	—	—	X

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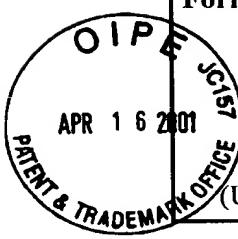
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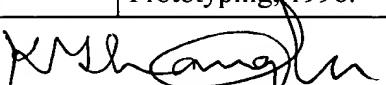
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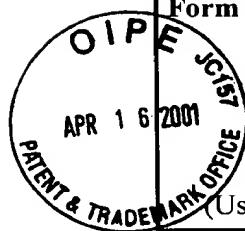


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		Group	Unknown
		Page 4 of 4	

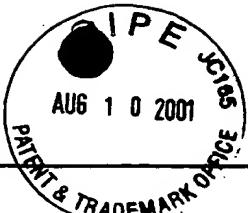
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<i>John Doe</i> Examiner		Date Considered 4/13/04

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**Form 1449 (Modified)**

**Information Disclosure  
Statement By Applicant**

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Application No.:

BRIDP004  
09/724,585

Applicant:

BEARDSLEE et al.

Filing Date

Group

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KM	2	5,831,868	11/03/98	Beausang et al.	364	489	12/09/97
KM	3	5,905,883	05/18/99	Kasuya	395	500	04/15/96
KM	4	5,991,523	11/23/99	Williams et al.	395	500.19	03/18/97

**Foreign Patent or Published Foreign Patent Application**

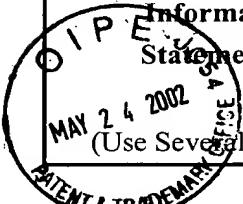
Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No

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Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
KM	5	PCT International Search Report, re PCT/US 00/32543, 28.06.01
KM	6	U.S. Patent Application No. 09/724,840, filed 11/28/00
KM	7	U.S. Patent Application No. 09/724,839, filed 11/28/00
KM	8	U.S. Patent Application No. 09/724,702, filed 11/28/00
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		Group	2824



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KJN	D.	6,157,210	12/2000	Zaveri et al.	—	—	
KJN	E.	6,182,268 B1	01/2001	McElvain	—	—	
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Examiner <i>KJN</i>		Date Considered 4/14/04

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Examiner	K. Shangguan	Date Considered 4/13/04

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